

Notice of References Cited

Application/Control No.

10/631,928

Applicant(s)/Patent Under
Reexamination
TEOH ET AL.

Examiner

Victor X. Nguyen

Art Unit

3734

Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-7,128,073	10-2006	van der Burg et al.	128/887
*	B	US-6,454,780	09-2002	Wallace, Michael P.	606/151
*	C	US-6,344,048	02-2002	Chin et al.	606/200
	D	US-			
	E	US-			
	F	US-			
	G	US-			
	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
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	V	
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	X	

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